

<b>Notice of References Cited</b>	Application/Control No. 09/784,352	Applicant(s)/Patent Under Reexamination HEUER, JOERG	
	Examiner Chongshan Chen	Art Unit 2172	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,233,578	05-2001	Machihara et al.	707/10
	B	US-6,345,269	02-2002	Kappenberger et al.	707/3
	C	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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